High Performance Analog Products

Tucson Corporation

Analytical Services

Reliability Report For TPS793285YEQ

New model qualification

09/18/2003

Texas Instruments High Performance Analog Products

Approved by:

Mark Yampolsky Supervisor/Reliability Engineering The TPS793285YEQ is qualified and fully meets the Texas Instruments quality and reliability standards for High Performance Analog Products per the testing described below.

Packaging Information		Manufacturing Information		
Assembly Site:	Unitive/TI-Tuc	son	Die Name:	ALBD79118AAW
Package Type:	WCSP/YEG		Die Size:	55 x 33 mils
Solder Bump Alloy:	63%/37% Tin/I	Lead	Mask Revision:	A
Solder Bump Diameter:	170µm		Wafer Fab Site:	DFAB (Dallas)
Bump Pitch:	500μm		Process:	LBC3S
Number of Solder Bumps:	5		Technology:	CMOS
Wafer Coating Material:	LC2850		Metal 1:	TIW/ALSiCu 0.5%
Redistribution Layer 1:	Electroplated C	Copper	Metal 2:	TIW/ALSiCu 0.5%
Flammability Rating	UL94 V-O and	l	Metal 3:	N/A
	IEC Standard 6	95-2-2		
Moisture Sensitivity Level	1		Passivation:	12kA CN
Reflow Temperature	240°C		Transistor Count:	400

Thermal Information

Absolute Max Junction Temp T _{J-MAX}	-40°C to 125°C
Recommended Junction Temp T _J	<125°C
$ heta_{ m JC}$	3.562°C/W
$ heta_{ m JB}$	N/A
SpecificationOperating Temperature T _A	-40°C to 85°C
Lead SolderingTemperature 1.6mm from case	N/A
Storage Temperature T _{STG}	-65°C to 150°C

Qualification Evaluation & Results:New model qualification in Nanostar package with Redistribution and Ti-Cu.

Qualification Material				
HTOL assem/wafer/lot:	B-0309053-03-H0/3035742	Latch Up assem/wafer/lot	B-0309053-03-HD/3035743	
			B-0309053-03-HD/3036157	
HAST assem/wafer/lot:	B-0309053-03-H0/3035742	ESD assem/wafer/lot	B-0309053-03-HD/3035743	
			B-0309053-03-HD/3036157	
Autoclave assem/wafer/lot:	B-0309053-03-H0/3035742	X-Ray assem/wafer/lot	N/A	
Temp Cycle assem/wafer/lot:	B-0309053-03-HD/3035743	MSL assem/wafer/lot	B-0309053-03-HD/3035743	
	B-0309053-03-HD/3036157		B-0309053-03-HD/3036157	

Qualification by Similarity (QBS):

Reliability data on similar packages and wafer fab processes may be used to support generic qualifications as approved by QRE.

Reliability Test Results

Test	Conditions	Lot 1	Lot 2	Lot 3	QBS Reference
		SS/F	SS/F	SS/F	
Life Test	150°C, 307 Hrs.	348/0			
HAST	130°C, 85%RH, 33.5 psia, 100 Hrs.	231/0			
Autoclave	121°C, 15 psia, 100%RH, 168 Hrs.	239/0			
Temp Cycle	-40 C to 125C, 500 cycles	239/0			
BLR Temp Cycle	-40°C to 125°C, 1230 cycles, 5°C/ min Temp Ramp Rate, 12 min dwell	35/0			
BLR 3 Point Bend Test	Strain Rate 5 mm/min., 85 mm span	8/0			
BLR Key Push Test	100 cycles/min, 1300μ ^a displacement = 2.7 mm max	8/0			
BLR Drop Test	50 cm	8/0			
ESD	HBM/500 volts	3/0			
	HBM/1000 volts	3/0			
	HBM/1500 volts	3/0			
	HBM/2000 volts	3/0			
	HBM/3000 volts	3/0			
	HBM/4000 volts	3/2			
	CDM/100 volts	3/0			
	CDM/200 volts	3/0			
	CDM/500 volts	3/0			
	CDM/1000 volts	3/0			
Latch Up		6/0			
Elec. Charac. over Temp	PDS	15/0			
Physical Dimensions		15/0			
Flammability- WSP		15/0			OPA2347YED
Manufacturability		Passed			
Bump Shear		150/0			
Hi Temp Storage Life Test	420Hrs@170°C	150/0			
Moisture Sensitivity Test	Level 1 240°C	12/0	12/0		

The FIT rate for this device is based upon qualification data from this qualification, process qualification data, and/or ongoing reliability monitoring. Current FIT information is available from the product quality web page.

MODEL	TPS793285YEQ			ACTIVATION	ENERGY (eV)
OVEN TEMP C°	150			0.7	
TEST DEVICES	348			(90% Confidence	e level)
PROCESS	LBC3S			(,
TROCLOS	LDC35				
	READ POINTS	TOTAL		DEVICE	
	(HOURS)	FAILURES	PASS	HOURS	
	307	0	348	106836	
		FAILRATE	MTTF		MTTF
TEMP.		(FITS)	(HOURS)		(YEARS)
25		6.84E+00	1.46E+08		16690.9
30		1.07E+01	9.32E+07		10644.3
35		1.66E+01	6.03E+07		6888.1
40		2.53E+01	3.96E+07		4519.8
45		3.80E+01	2.63E+07		3005.4
50		5.64E+01	1.77E+07		2023.8
55		8.28E+01	1.21E+07		1379.3
60		1.20E+02	8.33E+06		950.9
65		1.72E+02	5.81E+06		662.9
70		2.44E+02	4.09E+06		467.0
75		3.44E+02	2.91E+06		332.3
80		4.78E+02	2.09E+06		238.7
85		6.59E+02	1.52E+06		173.1
90		9.01E+02	1.11E+06		126.6
95		1.22E+03	8.19E+05		93.4
100		1.64E+03	6.09E+05		69.5
105		2.19E+03	4.56E+05		52.1
110		2.90E+03	3.45E+05		39.4
115		3.81E+03	2.62E+05		29.9
120		4.98E+03	2.01E+05		22.9
125		6.45E+03	1.55E+05		17.7

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